




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/078,074	CHUNG, SEUK HWAN	
	Examiner	Art Unit	
	Phylesha L. Dabney	2646	

ISSUE CLASSIFICATION									
ORIGINAL			CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
381	404	381	396	406					
INTERNATIONAL CLASSIFICATION									
	/								
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	/								
	/								
	/								
Phylesha Dabney 2/11/06 (Assistant Examiner) (Date)		 SINH TRAN SUPERVISORY PATENT EXAMINER (PPrimary Examiner) (Date)				Total Claims Allowed: 21			
 (Legal Instruments Examiner) (Date)						O.G. Print Claim(s) 1		O.G. Print Fig. 4	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA			<input type="checkbox"/> T.D.			<input type="checkbox"/> R.1.47		
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